

**Notice of References Cited**

Application/Control No.

10/822,189

Applicant(s)/Patent Under  
Reexamination  
HUNTLEY ET AL.

Examiner

NATHANIEL WIEHE

Art Unit

3745

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,276,122	10-2007	Devine et al.	118/719
*	B	US-5,785,796	07-1998	Lee, Hideki	156/345.24
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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